

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4671	29/603.07,603.09,603.11,603.13-603.16,603.18,605,606,609.ccls.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:40
L2	7803	(read adj sensor) or (Spin adj valve)	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:40
L3	9054	(read adj sensor) or (Spin adj valve) or (MR adj sensor)	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:41
L4	2789	(first adj gap) same (second adj gap)	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:41
L5	141	3 and 4	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:42
L6	23	1 and 5	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:41
L7	326	((first or second) adj gap) same resistance	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:42
L8	16	6 and 7	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:42
L9	14	8 and @ad<"20010102"	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:45
L10	732	360/313,319,321-324.ccls.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:45
L11	44	7 and 10	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:45
L12	40	3 and 11	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:45
L13	34	12 and @ad<"20010102"	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:03
L14	2	("6678127").PN.	USPAT; USOCR; JPO; DERWENT	OR	OFF	2004/12/20 09:48

L15	14	("4164770" "4983945" "5508614" "5587857" "5761009" "5771141" "5805390" "5818088" "5903415" "6034851" "6222361" "6246553" "6288880" "6424505").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/20 09:55
L16	4683	324/309-314,318,322,525,526,528.ccls.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:56
L17	2	3 and 16	USPAT; JPO; DERWENT	OR	ON	2004/12/20 09:56
L18	2	("3911899" "4992737").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/20 09:57
L19	6	("5508614").URPN.	USPAT	OR	ON	2004/12/20 10:00
L20	215	451/127,128.ccls.	USPAT	OR	ON	2004/12/20 10:00
L21	2	3 and 20	USPAT	OR	ON	2004/12/20 10:00
L22	0	7 and 20	USPAT	OR	ON	2004/12/20 10:00
L23	3192	451/5,41.ccls.	USPAT	OR	ON	2004/12/20 10:00
L24	1	7 and 23	USPAT	OR	ON	2004/12/20 10:01
L25	56	Hsiao-richard.in.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:01
L26	0	jarrat-james-d.in.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:01
L27	1	klaassen-emo-hilbrand.in.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:02
L28	2	mcfadyen-ian-robson.in.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:02
L29	7	moran-timothy-j.in.	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:02
L30	62	25 or 27 or 28 or 29	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:03
L31	29	3 and 30	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:03
L32	20	31 and 7	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:03
L33	16	32 and @ad<"20010102"	USPAT; JPO; DERWENT	OR	ON	2004/12/20 10:03

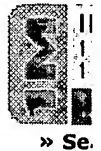
L34	1	3 and 4	JPO	OR	ON	2004/12/20 10:42
-----	---	---------	-----	----	----	------------------

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **1** of **1105713** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

(read sensor) <and> resistance

☐ Check to search within this result set
Results Key:**JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Study of magnetic tunnel junction read sensors**
Ho, M.K.; Tsang, C.H.; Fontana, R.E., Jr.; Parkin, S.S.; Carey, K.J.; Tao Pan; MacDonald, S.; Arnett, P.C.; Moore, J.O.;

Magnetism, IEEE Transactions on , Volume: 37 , Issue: 4 , July 2001

Pages:1691 - 1694

[\[Abstract\]](#)
[\[PDF Full-Text \(78 KB\)\]](#)
[IEEE JNL](#)

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved